

## **AMENDMENTS TO THE CLAIMS**

The following listing of claims will replace all prior versions, and listings, of claims in the application:

### **Listing of Claims:**

1. (Currently Amended) An apparatus for managing a liquid crystal substrate, comprising:

a data management section having a database;

a liquid crystal testing device operable to determine whether at least one of a panel and a substrate in the liquid crystal substrate has a defect, and ~~acquire to~~ send, to the data management section, defect information indicative of at least the defect and whether the at least one of the panel and the substrate is defective; ~~and~~

a liquid crystal repair device operable to receive the defect information from the data management section and to repair the defect based on the received defect information, ~~and acquire the liquid crystal repair device operable to send, to the data management section,~~ repair information that is indicative of ~~whether the defect at~~ least a position that is actually repaired, and to correct the received defect information in a case where the received defect information contains incorrect information with regard to the defect and generate corrected defect information as a part of the repair information; and

~~a data management section having a database adapted to record the defect information which is acquired from the liquid crystal testing device, and the repair~~

~~information which is acquired from the liquid crystal repair device, wherein:~~

said data management section is operable to record, in the database, the defect information sent from the liquid crystal testing device and the repair information sent from the liquid crystal repair device;

said data management section is operable to redetermine the presence of the defect based on comparison between the defect information and the repair information which are recorded in said database;

~~said liquid crystal repair device is operable to correct the defect information to generate corrected defect information when the defect information is different from the repair information with regard to the defect; and~~

said data management section is operable to update the defect information recorded in said database with the corrected defect information.

2. (Original) The liquid crystal substrate managing apparatus according to claim 1, wherein said data management section stores a recipe information for defining specifications of the substrate and panel in said database, said recipe information being edited freely.

3. (Original) The liquid crystal substrate managing apparatus according to claim 2, wherein said data management section edits the recipe information by exchange of information with a terminal connecting to the data management section.

4. (Currently Amended) A method for managing a liquid crystal substrate comprising:

~~causing a liquid crystal testing device to determine~~determining whether at least one of a panel and a substrate in the liquid crystal substrate has a defect;

~~and acquire~~receiving, from the liquid crystal testing device, defect information indicative of at least the defect and whether the at least one of the panel and the substrate is defective;

~~causing a liquid crystal repair device to repairing~~receive the defect information from the database, to repair the defect based on the received defect information; ~~and acquires~~

~~receiving, from the liquid crystal repair device,~~ repair information indicative of at least a position that is actually repaired;

~~causing the liquid crystal repair device to correct the received defect information in a case where the received defect information contains incorrect information with regard to the defect, and to generate corrected defect information as a part of the repair information;~~

~~recording, in a database, the defect information which is acquired from a liquid crystal testing device, and the repair information which is acquired from a liquid crystal repair device;~~

~~redetermining the presence of the defect based on comparison between the defect information and the repair information which are recorded in the database;~~

~~correcting the defect information to generate corrected defect information when the defect indicated by the defect information is different from the defect indicated by the repair information with regard to the defect; and~~

~~updating the defect information recorded in said database with the corrected defect information.~~

5. (Original) The liquid crystal substrate managing method according to claim 4, further comprising:

recording a recipe information acquired from the liquid crystal testing device in the database, the recipe information defining specifications of the substrate and panel and being edited freely.

6. (Canceled)

7. (Previously Presented) The liquid crystal substrate managing apparatus according to claim 1, wherein:

the repair information includes image information of a part of the at least one of the panel and the substrate that is actually repaired.

8. (Previously Presented) The liquid crystal substrate managing apparatus according to claim 1, wherein:

said data management section is operable to acquire trend information for defects of a plurality of liquid crystal substrates, by applying statistical processing with respect to the defect information and the repair information recorded in the database.

9. (Canceled)

10. (Previously Presented) The method for managing a liquid crystal

substrate according to claim 4, wherein:

the repair information includes image information of a part of the at least one of the panel and the substrate that is actually repaired.

11. (Previously Presented) The method for managing a liquid crystal substrate according to claim 4, further comprising:

acquiring trend information for defects of a plurality of liquid crystal substrates, by applying statistical processing with respect to the defect information and the repair information recorded in the database.

12. (Previously Presented) The liquid crystal substrate managing apparatus according to claim 1, wherein:

the corrected defect information is generated as a part of the repair information; and

the defect information is updated when the repair information includes the corrected defect information.

13. (Previously Presented) The method for managing a liquid crystal substrate according to claim 4, wherein:

the corrected defect information is generated as a part of the repair information; and

the defect information is updated when the repair information includes the corrected defect information.

14. (New) An apparatus for managing a liquid crystal substrate comprising:  
a data management section having a database;

a liquid crystal testing device operable to determine whether at least one of a panel and a substrate in the liquid crystal substrate has a defect, and to send, to the data management section, defect information indicative of at least the defect and whether the at least one of the panel and the substrate is defective; and

a liquid crystal repair device operable to receive the defect information from the data management section and to repair the defect based on the received defect information, the liquid crystal repair device operable to send, to the data management section, repair information that is indicative of at least a position that is actually repaired, and to correct the received defect information in a case where the received defect information contains incorrect information with regard to the defect and generate corrected defect information, wherein:

said data management section is operable to record, in the database, the defect information sent from the liquid crystal testing device and the repair information sent from the liquid crystal repair device; and

said data management section is operable to update the defect information recorded in said database with the corrected defect information.